•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•

MATERIAL SUPPORT

Metal Recommendations for Probe Needle.

01. INTRODUCTION Probe card company meet

O2. MARKET & TREND Service for wafer probe card

03. PROBLEM & SOLUTION Materiel & Method

O4. BUSINESS MODEL Add a short description



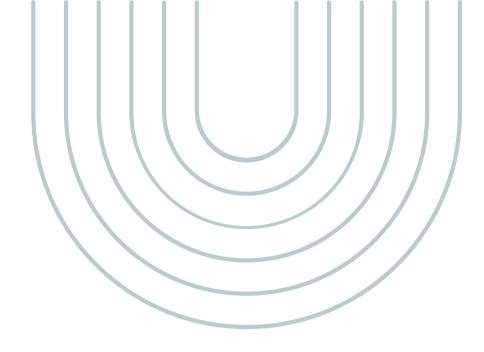


TABLE OF CONTENT

The mother of chips, the grand parents of Al. So, how can we check it is usable?



PROBE CARD

Current testing to determine the usability of wafers.

PROBE NEEDLES

Assessing the stress and current characteristics





LONG DESCRIPTION FOR PURPOSE

The onset of the **5G era signifies a profound shift in telecommunications**, heightening the necessity for components capable of handling high-speed signals with minimal attenuation. One significant challenge lies in the inadequacy of the length and material of measurement probes within **AP chips**, **HPC**, **and automotive technology to meet the surging demand**.

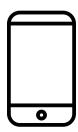
Our **innovative strategy** directly confronts this challenge. **By shortening probe lengths and enhancing electrical specifications**, we not only address current limitations but also future-proof our solutions. This is especially crucial in automotive technology, where the transition to autonomous vehicles and advanced driver-assistance systems (ADAS) necessitates robust components.

At the core of our approach lies the integration of an automated system identifying alloy characteristics highly valued by customers. This ensures consistency and reliability in probe performance, aligning perfectly with the rigorous demands of the 5G landscape. Furthermore, our solution exceeds mere compliance with 5G standards; it sets a new benchmark for probe durability and longevity. By extending probe lifespan through innovative design and materials, we reduce the frequency of replacements and maintenance, ultimately lowering costs.

The benefits of our approach ripple throughout the manufacturing ecosystem, including **heightened measurement accuracy**, **minimized signal degradation**, **prolonged probe lifespan**, enhanced operational efficiency and cost–effectiveness. Leveraging insights from market trends and customer feedback, we have identified strategic opportunities for **collaboration with material suppliers**.

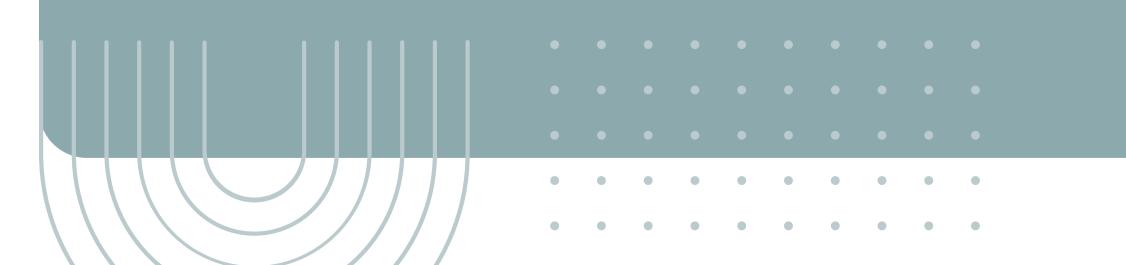
These **partnerships hold the potential to unlock new frontiers** in material science, paving the way for the development of advanced materials tailored to the needs of next-generation telecommunications infrastructure. Consequently, our probes not only excel in the realm of 5G but also offer promise for applications in emerging technologies such as the Internet of Things (IoT) and smart cities.

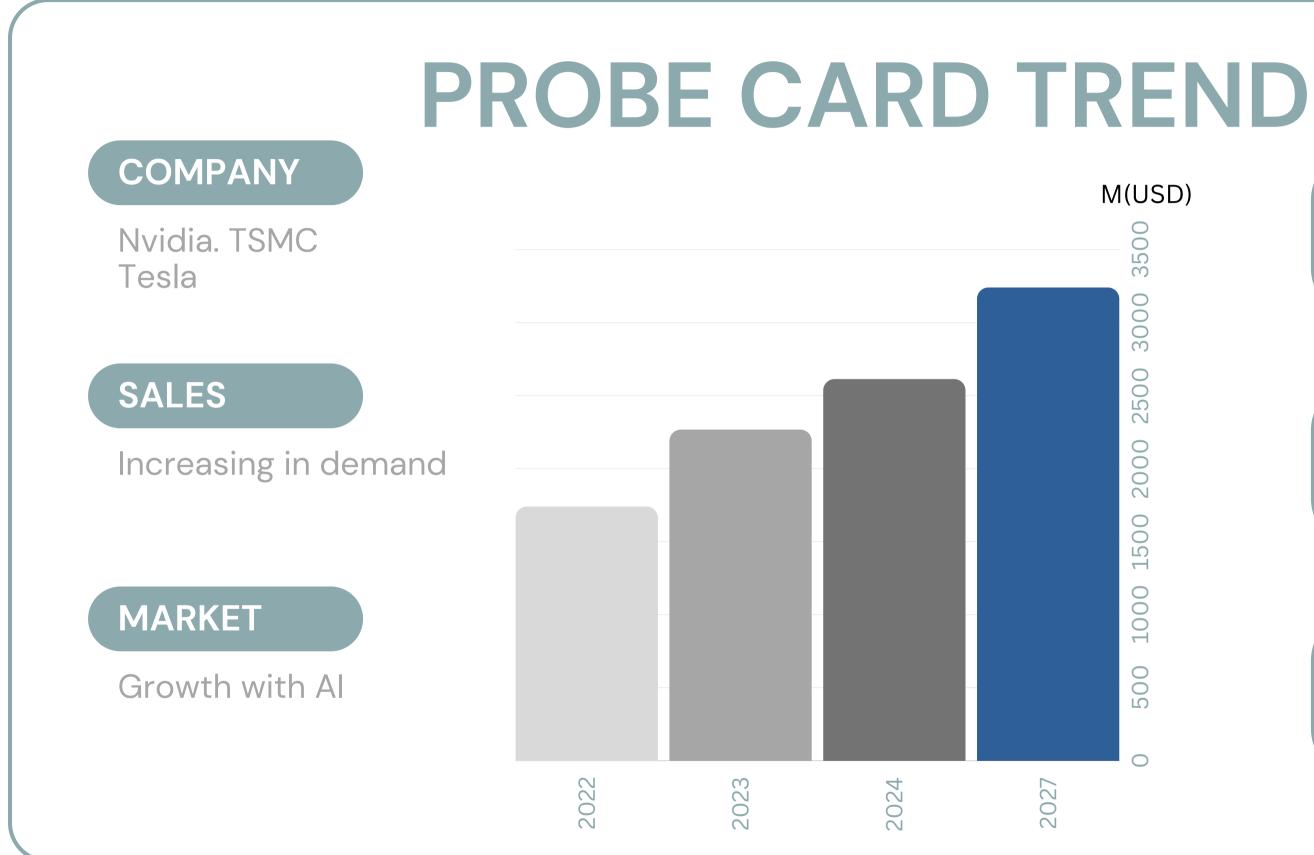
In essence, our dedication to innovation and collaboration positions us as a driving force in the probe card industry, poised to shape the future of telecommunications and unlock unprecedented possibilities in the 5G era and beyond.





MARKET & TREND Service for wafer probe card





M(USD)

3500

 \bigcirc

3000

2500

2000

1500

1000

500

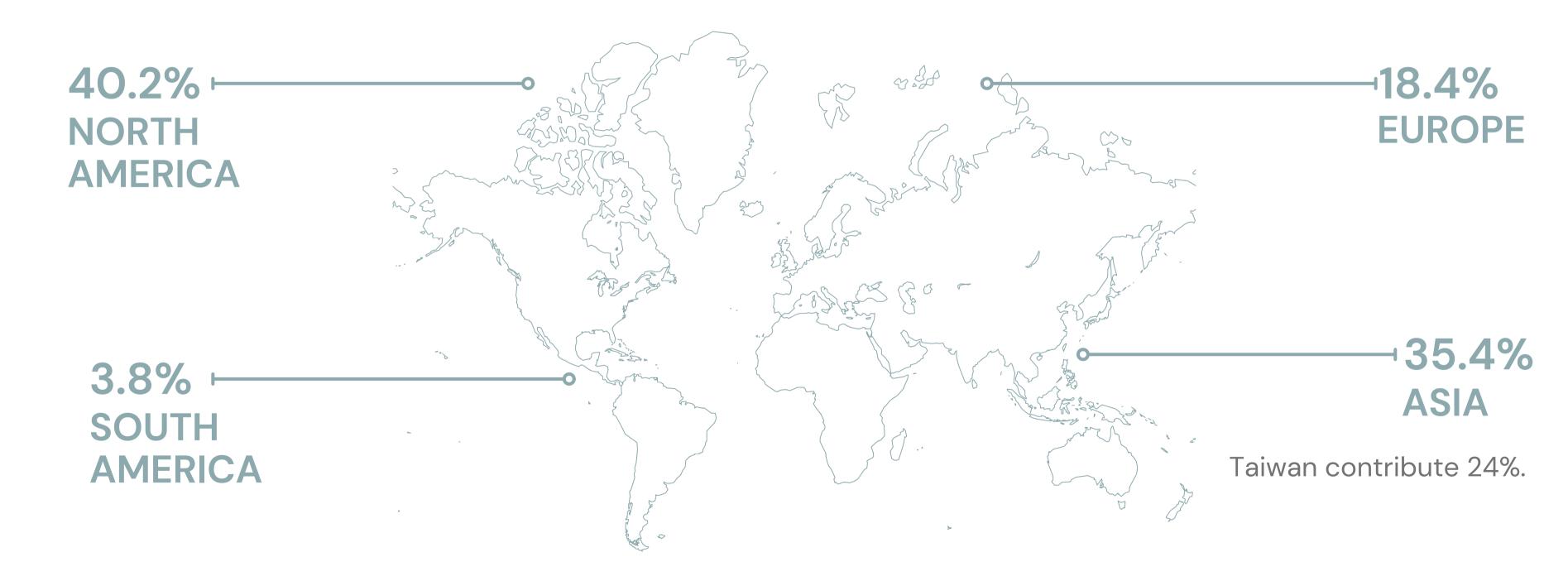
0

56.4% Semiconductor 2023 YoY

>\$2267M Total revenue in 2023

> 9.4% 2023-2027 CAGDR

GLOBAL MARKET



•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•
•	•	•	•	•	•	•	•	•	•



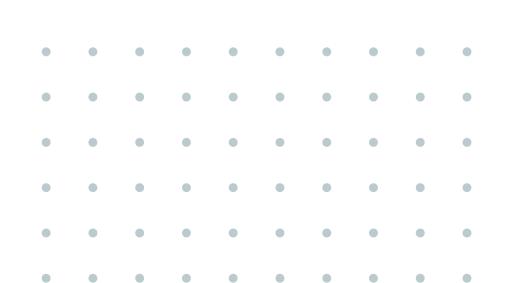
SOLUTION Material & Method.



- Rapid product iteration
- Timeliness in production
- Metal properties are interdependent

- Targeting search for scholarly articles on probe design.
- Compiling metal material data to assess the performance of key features in a new alloy. Investigating the numerical performance of alloy materials, with a focus on stress response and signal behavior.

SOLUTION



FLOW TABLE



WEBSITE MANAGEMENT

CRAWLER

KEY WORD





MS

Q Search

probe

Review on recent progress in Al-Mg-Si 6xxx conductor alloys

Proc.

Search | arXiv e-print repository

Afterward, by integrating the expertise of multiple specialized components, we propose an MoE-proximal policy optimization (PPO) approach to solve the formulated problem.

Search | arXiv e-print repository

Journal ref: Proc.

Search | arXiv e-print repository

Journal ref: Proc.

Search | arXiv e-print repository

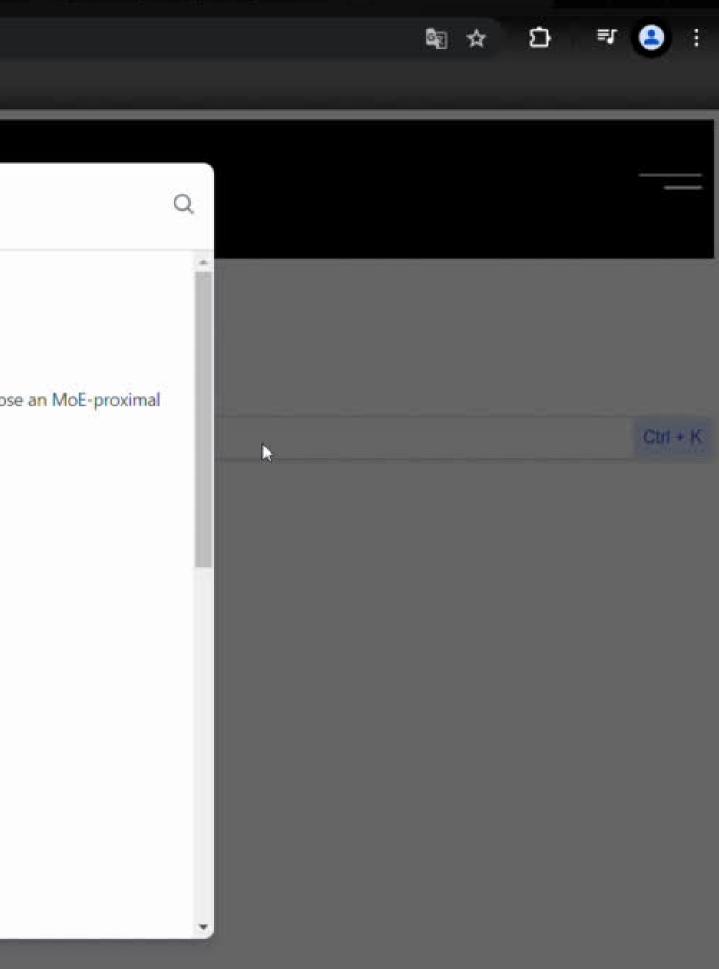
Journal ref: Proc.

Search | arXiv e-print repository Journal ref: Proc.

Search | arXiv e-print repository Journal ref: Proc.

Search | arXiv e-print repository

GUIDING USERS





1. Material recommandation 2. Decrease the information barrier between Card company& Material Suppliers

Integrate IC designer PCB Semiconduct products

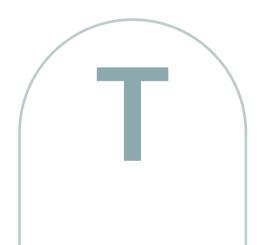






Material manufacturers build similar recommandtion system

NO Material production capacity



PARTNERING WITH VECTARA FOR THE FUTURE

DOMAIN KNOWHOW

RAG ADVOCATE

Provide insights and research capacity on Probe card and Materials to enter the market. Optimizing based on Vectara's modules and the RAG framework.

TECHNICAL PARTNERS

Continuously enhancing the accuracy of GPT, and expanding the achievable application scenarios.

• •		•	•	•	•	•	•	•	
	-	•			•	•	•	•	
Hav									

YOU

ve any question?